



Description

The XPX2N12FD is silicon N-channel Enhanced

VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

#### **General Features**

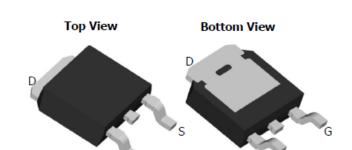
V<sub>DS</sub> = 200V I<sub>D</sub> =18A

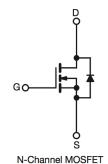
 $R_{DS(ON)}$  < 150m $\Omega$  @  $V_{GS}$ =10V (Type: 120m $\Omega$ )

### **Application**

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)





**Package Marking and Ordering Information** 

	<u> </u>			
Product ID	Pack	Marking	Qty(PCS)	ı
XPX2N120FD	TO-252-3L	XXX YYYY	2500	ì

### Absolute Maximum Ratings (T<sub>c</sub>=25°Cunless otherwise noted)

0	B	Value		
Symbol	Parameter	TO-252	Unit	
VDSS	Drain-Source Voltage (V <sub>GS</sub> = 0V)	200	V	
ID	Continuous Drain Current	18	А	
IDM	Pulsed Drain Current (note1)	72	А	
VGS	Gate-Source Voltage	±20	V	
E <sub>AS</sub> Single Pulse Avalanche Energy (note2)		340	mJ	
IAR Avalanche Current (note1)		15	А	
Ear	Repetitive Avalanche Energy note1)	8.3	mJ	
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)	104	W	
TJ, Tstg	Operating Junction and Storage Temperature Range	-55~+150	°C	
RthJC	Thermal Resistance, Junction-to-Case	1.2	°C/W	
RthJA	Thermal Resistance, Junction-to-Ambient	62.5	°C/W	



### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

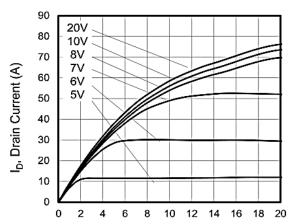
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	200	220		V
IDOO	V <sub>DS</sub> = 200V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 25°C				5	^
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 160V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C			100	μA
IGSS	Gate-Source Leakage	V <sub>GS</sub> = ±20V			±100	nA
VGS(th)	Gate-Source Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.0	1.6	3.0	V
RDS(on)	Drain-Source On-Resistance (Note3)	V <sub>GS</sub> = 10V, I <sub>D</sub> = 9A		120	150	mΩ
Ciss	Input Capacitance			1318		
Coss	Output Capacitance	$V_{GS} = 0V,$ $V_{DS} = 25V, f = 1.0MHz$		180		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	201,1 1.002		75		
Qg	Total Gate Charge			41		nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DD</sub> = 160V, I <sub>D</sub> = 18A, V <sub>GS</sub> = 10V		5.5		
$Q_{gd}$	Gate-Drain Charge		1	19.5		
td(on)	Turn-on Delay Time		-	24		
t <sub>r</sub>	Turn-on Rise Time	V = 100V I = 10A B = 25 O		45		ns
td(off)	Turn-off Delay Time	$V_{DD} = 100V, I_D = 18A, R_G = 25 \Omega$	1	101		
t <sub>f</sub>	Turn-off Fall Time		-	95		
ls	Continuous Body Diode Current	T - 25.90			18	^
ISM	Pulsed Diode Forward Current	T <sub>C</sub> = 25 °C	-		72	Α
V <sub>SD</sub>	Body Diode Voltage	T <sub>J</sub> = 25°C, I <sub>SD</sub> = 18A, V <sub>GS</sub> = 0V			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	\\ _ 0\\  _ 404 di \d+ 4004 fi		230		ns
Qrr	Reverse Recovery Charge	$V_{GS} = 0V,I_{S} = 18A, di_{F}/dt = 100A /\mu s$		1.8		μC

#### Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The EAS data shows Max. rating . IAS = 15A, VDD = 50V, RG = 25  $\Omega$ , Starting TJ = 25  $^{\circ}$ C
- 3、The test condition is Pulse Test: Pulse width ≤ 300 $\mu$ s, Duty Cycle ≤ 1%
- 4. The power dissipation is limited by 150  $^{\circ}\mathrm{C}$  junction temperature
- 5、The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



### **Typical Characteristics**



 $V_{DS}$ , Drain-to-Source Voltage (V) Figure 1. Output Characteristics (T<sub>J</sub> = 25°C)

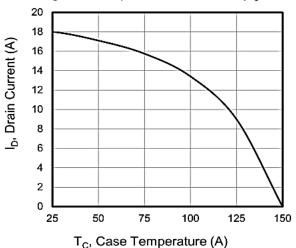


Figure 3. Drain Current vs. Temperature

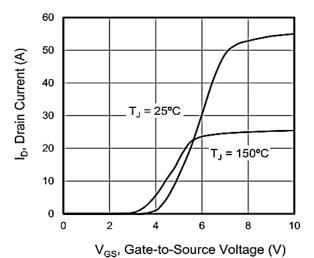
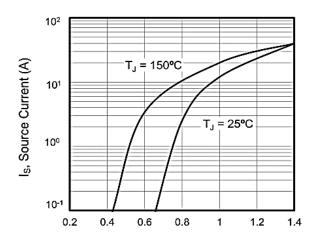
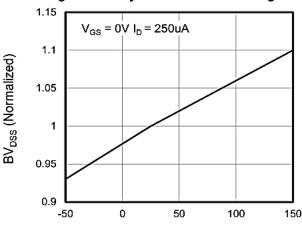


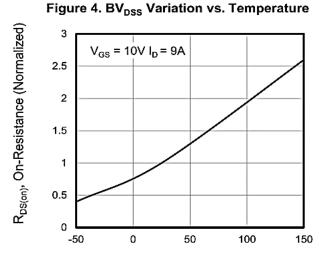
Figure 5. Transfer Characteristics



 $V_{SD}$ , Source-to-Drain Voltage (V) Figure 2. Body Diode Forward Voltage



T<sub>J</sub>, Junction Temperature (°C)

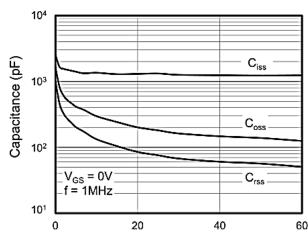


T<sub>J</sub>, Junction Temperature (°C)

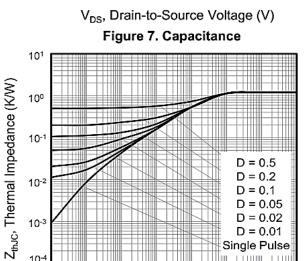
Figure 6. On-Resistance vs. Temperature







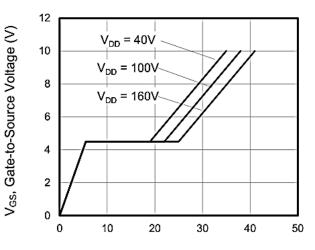




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T<sub>p</sub>, Pulse Width (s) Figure 10. Transient Thermal Impedance

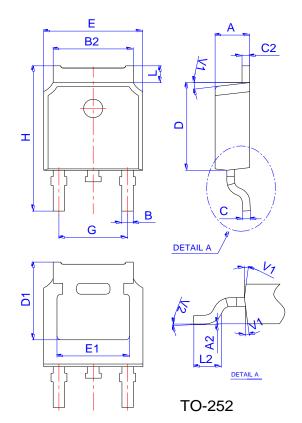
= 0.01 Single Pulse



Q<sub>g</sub>, Total Gate Charge (nC) Figure 8. Gate Charge

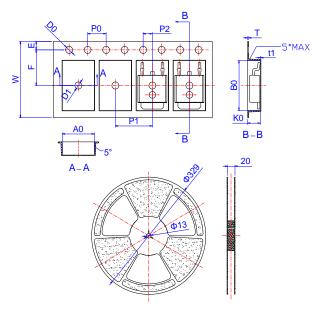


# Package Mechanical Data: TO-252-3L



	Dimensions					
Ref.	Ref. Millimete		rs Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
В	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
С	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
Н	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

# **Reel Spectification-TO-252**



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60			
P0	3.90	4.00	4.10			
P1	7.90	8.00	8.10			
P2	1.90	2.00	2.10			
A0	6.85	6.90	7.00			
В0	10.45	10.50	10.60			
K0	2.68	2.78	2.88			
Т	0.24		0.27			
t1	0.10					
10P0	39.80	40.00	40.20			



# XPX2N120FD

### 200V N-Channel Enhancement Mode MOSFET

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time		
Pb device	<b>245℃±5℃</b>	5sec±1sec		
Pb-Free device	260℃+0/-5℃	5sec±1sec		



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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